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Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023 Based on structural similarity

Supplier		User Part Number						
Nexperia B.V.		BAS21TH-Q						
Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		Part Description						
		Nexperia DHAM Small Signal Bipolar Diode						
		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113	.,					
		Bake Tamb = 125 °C	24 hours					
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours					
# A1	Preconditioning	Reflow soldering	3 cycles	1514	64430	0		
	5	MIL-STD-750-1						
	HTRB	M1038 Method A						
		$T_j = T_jmax$, $Vr = 100\%$ of max. datasheet						
# B1	Bias	reverse voltage	1000 hours	110	4920	0		
			2000 110010	110	1520	0		
	тс	JESD22-A104						
# A4	Temperature Cycling	-65 °C to Timax, not to exceed 150°C	1000 cycles	311	14080	0		
			1000 070.00	011	1.000	0		
	UHAST	JESD22-A118						
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %						
", , , , , , , , , , , , , , , , , , ,		JESD22-A102	—96 hours	311	14080	0		
	AC	Tamb = $121 ^{\circ}$ C, RH = $100 ^{\circ}$						
# A3 alt	Autoclave	Pressure = $205 \text{ kPa} (29.7 \text{ psia})$						
# AS dit	Autoclave							
	H3TRB	JESD22-A101						
	High Humidity High	Tamb = $85 ^{\circ}$ C, RH = 85% , VR = 80% of						
# A2 alt	Temperature Reverse Bias		1000 hours	311	14080	0		
# A2 alt	remperature reverse blas		1000 Hours	211	14000	U		
	IOL	MIL-STD-750 Method 1037						
# AF		ton = toff, devices powered to insure ΔTj =	1000 hours	212	14120	0		
# A5	Intermittent Operating Life	TOO -C TOF TOODO CYCles	1000 hours	312	14120	0		
	2011							
# 60	RSH Desistance to Colder Uset	JESD22-A111	10 -	260	0070	0		
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	269	8070	0		
	SD California billion	1 CTD 000		222				
# C10	Solderability	J-STD-002		222	6660	0		

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Small Signal Bipolar Diode	4920	0	0,86	1,16E+09

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